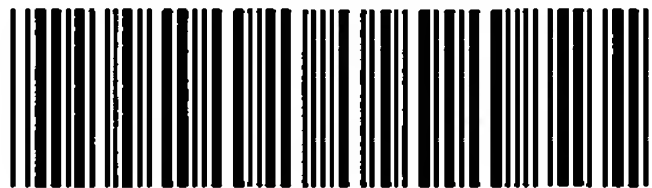


Search Notes



Application/Control No.

10/632,467

Examiner

Hiep T. Nguyen

Applicant(s)/Patent under Reexamination

WATANABE ET AL.

Art Unit

2187

SEARCHED

Class	Subclass	Date	Examiner
711	162	7/22/05	H
707	204	6	u
714	6	u	u

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST search his. is attached	7/22/05	142
NPL search using terms similar to EAST search	u	u
Inventorship search.	u	u